

Group Art Unit: Unassigned
Examiner: Unassigned

Applicants	:	Masakatsu SAIJYO et al.
Serial No.	:	Unassigned
Filed	:	August 27, 2003
For	:	METHOD OF MEASURING CONTACT RESISTANCE OF PROBE AND METHOD OF TESTING SEMICONDUCTOR DEVICE
Attorney Ref.	:	OKI 373

**PRELIMINARY
AMENDMENT**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Prior to examination on the merits, please amend the application as follows: